

Search Notes

Application/Control No.

10/720,540

Examiner

David Buttner

Applicant(s)/Patent under
Reexamination

HAYASHI ET AL.

Art Unit

1712

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	2/16/2006	DB